

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L8	1	(FPGA PLD) and (configuration adj (controller processor)) and BIST	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 14:21
L5	270	(FPGA PLD) and (configuration adj (controller processor))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 14:21
L7	12	L6 not L4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 14:16
L6	23	L5 and L3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 14:16
L2	55	PLD and "configuration controller"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 14:15
L4	11	L2 and L3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 14:08
L3	15134	(714/2,710,711,715,718-720,733 365/200,201 326/10,38,39,41).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 14:08
S35	15134	(714/2,710,711,715,718-720,733 365/200,201 326/10,38,39,41).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/26 14:07

## EAST Search History

S39	52	S35 and S38	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 16:26
S38	171	(concurrent\$2 simultaneous\$2) near4 (BIST self-test)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 16:25
S37	109	S36 and (BIST self-test)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 16:25
S36	1074	S35 and (defect\$3 near3 column) and ((redundant spare) near2 column)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 16:23
S25	11217	(714/710,711,715,718-720,733 365/200,201).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 16:21
S34	2	(configuration near2 control\$3) and ((BIST "built in self test" "built-in self-test" self-test "self test") near2 control\$3) and ("random access memory" RAM SRAM "volatile memory") same (redundant near3 column))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 10:42
S33	2	(configuration near2 control\$3) and ((BIST "built in self test" "built-in self-test" self-test "self test") near2 control\$3) and ("random access memory" RAM SRAM "volatile memory") same (redundant near3 column)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 10:42
S32	117	(configuration near2 control\$3) and ((BIST "built in self test" "built-in self-test" self-test "self test") near2 control\$3) and ("random access memory" RAM SRAM "volatile memory")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 10:41

## EAST Search History

S31	0	S29 and (self-test "self test")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 10:37
S30	31	"L10" and (self-test "self test")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 10:35
S29	10	S25 and ((FPGA PLD PLA) same (RAM memory)) and (redundan\$2 (column row)) and ((program\$4 configur\$5) near4 (volatile near2 memory))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 10:33
S28	176	S25 and ((FPGA PLD PLA) same (RAM memory)) and (redundan\$2 (column row))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 10:10
S26	234	S25 and ((FPGA PLD PLA) same (RAM memory))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 10:09
S27	1	S25 and S23	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 10:07
S24	0	S22 not S23	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 10:06
S23	6	((FPGA PLD PLA) same (RAM memory)) and ((BIST self-test) same (BISR self-repair))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 10:06

## EAST Search History

S22	6	((FPGA PLD PLA) same (RAM memory)) and ((BIST self-test\$3) same (BISR self-repair\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 10:05
S20	6	((FPGA PLD PLA) same (RAM memory)) and ((BIST self-test) same (BISR self-repair))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/25 10:05
S21	5	S20 not S19	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 18:34
S19	1	((FPGA PLD PLA) with (RAM memory)) and ((BIST self-test) same (BISR self-repair))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 18:34
S18	1	((FPGA PLD PLA) with ((RAM memory) near2 array)) and ((BIST self-test) same (BISR self-repair))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 18:34
S17	0	((FPGA PLD PLA) with ((RAM memory) near2 array)) same ((BIST self-test) same (BISR self-repair))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 18:32
S15	1	configur\$3 with (FPGA PLD "programmable logic device" "programmable logic") and (BIST self-test) and ((redundan\$2 repairable) near3 (memory column))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 18:09
S16	9	(program\$4 configur\$3) with (FPGA PLD "programmable logic device" "programmable logic") and (BIST self-test) and ((redundan\$2 repairable) near3 (memory column))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 16:49

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S14	1	configur\$3 with (FPGA PLD "programmable logic device" "programmable logic") and (BIST self-test) and (redundan\$2 near3 (memory column))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 16:30
S13	179	configur\$3 with (FPGA PLD "programmable logic device" "programmable logic") and (BIST self-test)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 16:28
S12	5154	configur\$3 with (FPGA PLD "programmable logic device" "programmable logic")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 16:27
S9	26	(FPGA PLD "programmable logic device" "programmable logic") and \$2RAM and (redundan\$2 near3 column) and (BIST self-test)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 16:25
S11	0	S9 and ((setting stor\$3) near3 error)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 15:37
S10	0	(FPGA PLD "programmable logic device" "programmable logic") and \$2RAM and (redundan\$2 near3 column) and (BIST self-test) and ((setting stor\$3) near3 error near2 flag)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 15:37
S5	29	S2 and (FPGA PLD "programmable logic device" "programmable logic" "programmable memory")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 15:31
S8	15	S7 and (redundan\$2 repair\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 15:01

## EAST Search History

S7	26	S5 not S6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 15:01
S6	3	S5 and BIST	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 14:55
S2	41	("3995261" "4020469" "4700187" "4899067" "5153880" "5255227" "5459342" "5485102" "5498975" "5513144" "5592102" "5742556" "5764577" "5777887" "5889413" "5914616" "6166559" "6167558" "6344755" "6356514" "6560740").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 14:54
S4	5	09/924365 and Ling	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 14:43
S3	5	09/924365	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 14:43
S1	39	("3995261" "4020469" "4700187" "4899067" "5153880" "5255227" "5459342" "5485102" "5498975" "5513144" "5592102" "5742556" "5764577" "5777887" "5889413" "5914616" "6166559" "6167558" "6344755" "6356514").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/24 14:42